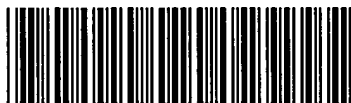


Search Notes

Application No.

09/545,288

Examiner

Minh Trinh

Applicant(s)

AYALA ET AL.

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
29	600, 825, 829, 827, 830, 846	1/18/2005	mt
235	492, 487,		
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257	679, 728		
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343	866, 873		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text, image and inventor name searched (see print out)	1/18/2005	mt
Reviewed 5,598,032 and 5,809,633 and all references cited therefrom.		

Notice of References Cited

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Applicant(s)/Patent Under
Reexamination
AYALA ET AL.

Examiner

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Art Unit

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Page 1 of 1

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	B	US-6,049,461	04-2000	Haghiri-Tehrani et al.	361/737
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	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.